



Deep Learning Based Machine Fault Diagnosis and Prognosis

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Message from the Guest Editor

Dear Colleagues,

In the age of Internet of Things and Industrial 4.0, massive real-time data are collected from health monitoring systems for the purpose of fault diagnosis and prognosis. The health monitoring big data are characterized by large volume and diversity. Effectively mining features from such data, accurately diagnosing the faults and predicting the remaining useful life (RUL) of the equipment in use with new advanced methods become new issues in the field of prognostics and health management (PHM). In recent years, deep learning methods are becoming a popular approach for big data process and analysis. Deep learning represents an attractive option to process big data for fault diagnosis and prognosis as deep learning has the ability to automatically select features that otherwise require much skill, time, and experience. This Special Issues call for papers that address developing effective and efficient deep learning based fault diagnosis and prognosis methods.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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